Fluctuations and Noise
23–26 May 2005
Austin, Texas USA

Submit an Abstract for this Conference

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This topical conference considers noise and fluctuations in devices and circuits. It covers both experimental and theoretical aspects of noise and fluctuations, experimental techniques and modeling and implementation issues in simulators. A tentative listing of the scope of the conference is given below.

Accepted papers will be published in the Proceedings of SPIE and extended selected papers may be published in a special issue of a scientific journal.

Presentations are solicited on the following and related areas:

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12/28/2004
• electronic devices and circuits - low frequency
• electronic devices and circuits - high frequency
• impact of geometrical down-scaling on device noise
• photonic devices and circuits
• emerging devices such as nanotubes, polymer devices etc.
• noise modeling - physical and circuit-based - in small and large signal operation
• amplitude modulation noise
• phase modulation noise
• noise in nanoelectronic, single-electronic and quantum devices
• noise in passive components
• noise measurements - practical considerations
• noise aspects in high speed digital circuits
• noise reduction techniques
• noise spectroscopy
• theoretical aspects of device and circuit noise computation
• RF MEMS.

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